

IN THE CLAIMS:

The status of each claim that has been introduced in the above-referenced application is identified in the ensuing listing of the claims. This listing of the claims replaces all previously submitted claims listings. Please amend the claims as follows:

1. (Original) A testing method for an integrated circuit of an integrated circuit device of a plurality of integrated circuit devices comprising:
storing an enhanced reliability testing flag associated with a unique identification code of each integrated circuit device of the plurality of integrated circuit devices for indicating whether each integrated circuit device requires enhanced reliability testing;
automatically reading the unique identification code of each integrated circuit device of the plurality of integrated circuit devices when each integrated circuit device of the plurality of integrated circuit devices forms a portion of a wafer;
accessing the enhanced reliability testing flag stored for each unique identification code of each integrated circuit device;
sorting the plurality of integrated circuit devices in accordance with whether their enhanced reliability testing flag indicates they are in need of the enhanced reliability testing; and performing the enhanced reliability testing for the integrated circuit devices requiring the enhanced reliability testing.

2. (Previously Presented) A reliability testing method for an integrated circuit of an integrated circuit device of a plurality of integrated circuit devices comprising:
storing a reliability testing flag associated with a unique identification code of each integrated circuit device of the plurality of integrated circuit devices for indicating whether each integrated circuit device requires further reliability testing;
automatically reading the unique identification code of each integrated circuit device of the plurality of integrated circuit devices;
accessing the reliability testing flag stored for each unique identification code of each integrated circuit device;

sorting the plurality of integrated circuit devices in accordance with whether their reliability testing flag indicates they are in need of the further reliability testing; and performing the further reliability testing for the integrated circuit devices requiring the further reliability testing.

3. (Previously Presented) A manufacturing method for an integrated circuit of an integrated circuit device of a plurality of integrated circuit devices comprising:
storing a reliability testing flag associated with a unique identification code of each integrated circuit device of the plurality of integrated circuit devices for indicating whether each integrated circuit device requires further reliability testing;
automatically reading the unique identification code of each integrated circuit device of the plurality of integrated circuit devices;
accessing the reliability testing flag stored for each unique identification code of each integrated circuit device;
sorting the plurality of integrated circuit devices in accordance with whether their reliability testing flag indicates they are in need of the further reliability testing; and performing the further reliability testing for the integrated circuit devices requiring the further reliability testing.